

Mean-Free-Path Dependence of the Losses From Trapped Magnetic Flux in SRF Cavities

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- It is well understood that to achieve optimal Q₀ performance, SRF cavities should be cooled in as small magnetic fields as possible.
- A rule of thumb is given in Padamsee: residual resistance will increase by 0.3 nΩ per mG of magnetic field.

Cavity Q ₀	Q ₀ in 10 mG, 0.3 nΩ/mG	ΔP _{diss} (0.3 nΩ/mG)	Q ₀ in 10 mG, 1 nΩ/mG	ΔP _{diss} (1 nΩ/mG)
1x10 ¹⁰	9x10 ⁹	11%	7x10 ⁹	40%
2.7x10 ¹⁰	2.1x10 ¹⁰	29%	1.4x10 ¹⁰	93%

At lower Q₀'s, the exact sensitivity didn't matter as much





Now that we are routinely dealing with higher Q_0 's and new cavity preparation techniques:

- How does this ratio change depending on cavity preparation/material parameters?
 - Is there anything different about how doped cavities react to magnetic fields?





- A. Gurevich predicts a higher sensitivity to trapped flux with lower mean free path.
 - In the dirty limit $R_{res} \sim \frac{1}{\ell^3}$
- The exact theoretical dependence is heavily dependent on the material parameter space.



A. Gurevich, Vortex hotspots in SRF Cavities. 7th SRF Materials Workshop, Jlab, July 16, 2012







 $R_{res} \, vs \, \Delta T_{vertical}$ in the Cornell HTC



- Romanenko et. al. first showed that residual resistance increased in nitrogen-doped cavities and 120°C baked cavities after a slow cool down.
- Recent results at Cornell and FNAL have further expanded upon these initial results.
- Larger transverse spatial temperature gradients during cool down lead to more efficient flux expulsion and lower residual resistance.

Large $\Delta T/\Delta x \rightarrow Lower R_{res}$

See MOBA08 and MOPB041





How then can we compare cavity sensitivities to magnetic fields while normalizing for cool down parameters?









- When a cavity becomes superconducting in a magnetic field, some of that field will be trapped in the cavity walls.
- This trapped magnetic field directly leads to additional residual resistance.









- Want to measure increase in R_{res} due to trapped flux as a function of material properties
 - 3 challenges:
 - 1. Control flux trapping/measure how much is trapped
 - 2. Measure R_{res} at low fields
 - 3. Extract material properties from RF surface impedance measurements





Experimental Setup







Fluxgate Measurements





R_s vs T



- More trapped flux leads to higher surface resistance.
- This surface resistance increase is seen only in the temperature independent residual resistance.
- Temperature dependent BCS resistance is unaffected by trapped flux.









Residual resistance from trapped flux is independent of E_{acc} up to medium field





Fitting of BCS Parameters

Penetration Depth vs Temperature



- Change in penetration depth is computed from change in resonance frequency.
- Penetration depth depends strongly on mean free path and T_c.
- This is fit using BCS theory to extract mean free path holding energy gap and residual resistance constant.



Surface Resistance vs Temperature

- Q₀ is sensitive to energy gap and residual resistance but not mean free path.
- Surface resistance vs temperature is fit using BCS theory to extract energy gap and residual resistance holding mean free path constant.







- 8 single-cell cavities were prepared with a variety of techniques.
 - 6 nitrogen doped cavities of varying doping levels
 - 2 "standard" treated cavities: one EP cavity and an EP+120^oC baked cavity





- Each cavity was cooled in a variety of magnetic fields leading to different amounts of trapped magnetic flux.
- Mean free path was extracted for each cavity.
- Sensitivity to trapped magnetic flux was found.



R_{res} vs Trapped Flux



Cavities with different preparations show very different sensitivities to trapped flux!



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Sensitivity parameter = $\frac{dR_{res}}{dB_{trapped}}$

- Stronger doping results in a higher sensitivity to trapped flux.
- All nitrogen-doped cavities tested showed a higher sensitivity than both the EP and EP+120°C baked cavities.





Results

N-Doping Temperature	Cavity	Mean Free Path [nm]	ε/k _B T _c	Sensitivity to Trapped Flux [nΩ/mG]
800°C	LT1-2	19±6	1.87±0.03	3.7±0.9
	LT1-3	34±10	1.91±0.03	3.1±0.5
	LT1-1	39±12	1.88±0.03	2.5±0.6
	LT1-4	47±14	1.89±0.03	2.2±0.2
	LT1-5	60±18	1.88±0.03	1.87±0.08
900°C	LT1-2	6±2	2.01±0.03	4.7±0.6
	NR1-3 (EP)	770±230	1.81±0.03	0.8±0.1
	NR1-3 (EP+120°C)	120±36 ⁺	1.96±0.03	0.6±0.05

+ 120°C bake only affects a fraction of the RF penetration layer – mean free path is found effectively by averaging over the whole RF layer



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Sensitivity vs MFP



Smaller mean free path results in higher sensitivity to trapped flux.





- This is the first systematic measurement of the dependence of residual resistance sensitivity to trapped magnetic flux on cavity preparation.
- Nitrogen-doped cavities have a lower mean free path → higher sensitivity
- These measurements explain why slow cool down affects nitrogen-doped cavities so much stronger than "standard" prepared cavities.

